

# N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY						
V <sub>DS</sub> (V)	100					
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	0.086				
Q <sub>g</sub> (Max.) (nC)	72					
Q <sub>gs</sub> (nC)	11					
Q <sub>gd</sub> (nC)	32					
Configuration	Single					

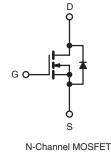
## **FEATURES**

- Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- · Dynamic dV/dt Rating
- Low Thermal Resistance
- Lead (Pb)-free Available



RoHS COMPLIANT





ABSOLUTE MAXIMUM RATINGS T	<sub>C</sub> = 25 °C, u	nless otherw	vise noted				
PARAMETER			SYMBOL	LIMIT	UNIT		
Drain-Source Voltage			V <sub>DS</sub>	100	V		
Gate-Source Voltage			V <sub>GS</sub>	± 20	- ·		
Continuous Drain Current	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 25 °C	1	18			
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C	I <sub>D</sub>	12	А		
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	68	1		
Linear Derating Factor				0.32	W/°C		
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	720	mJ		
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	17	A		
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	4.8	mJ		
Maximum Power Dissipation	T <sub>C</sub> =	25 °C	PD	48	W		
Peak Diode Recovery dV/dt <sup>c</sup>	•		dV/dt	5.5	V/ns		
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C		
Soldering Recommendations (Peak Temperature)	for	10 s		300 <sup>d</sup>			
Mounting Torque	6 22 or l	6.00 or M2 corous		10	lbf ⋅ in		
	6-32 or M3 screw		F	1.1	N · m		

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b.  $V_{DD} = 25 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 3.7 mH,  $R_G = 25 \Omega$ ,  $I_{AS} = 17 \text{ A}$  (see fig. 12). c.  $I_{SD} \le 17 \text{ A}$ , dI/dt  $\le 200 \text{ A}/\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 175 \text{ °C}$ .

d. 1.6 mm from case.

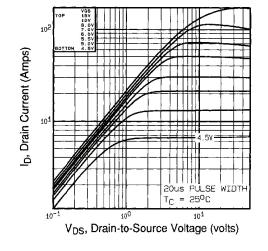
THERMAL RESISTANCE RAT	TINGS								
PARAMETER	SYMBOL	TYP.		MAX.		UNIT			
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 65			°C 111				
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 3.1				°C/W			
<b>SPECIFICATIONS</b> $T_J = 25 \ ^{\circ}C$ ,	unless otherw	vise noted							
PARAMETER	SYMBOL	TEST	CONDITI	ONS	MIN.	TYP.	MAX.	UNIT	
Static									
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> =	0 V, I <sub>D</sub> = 2	50 µA	100	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C,	I <sub>D</sub> = 1 mA	-	0.13	-	V/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$			1.0	-	3.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	V	<sub>GS</sub> = ± 20 '	V	-	-	± 100	nA	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 1$	100 V, V <sub>GS</sub>	s = 0 V	-	-	25		
		V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C			-	-	250	μA	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub>	= 10 A <sup>b</sup>	-	0.086	-	Ω	
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> =	50 V, I <sub>D</sub> =	10 A <sup>b</sup>	9.1	-	-	S	
Dynamic									
Input Capacitance	C <sub>iss</sub>				-	1700	-		
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0  MHz,  see fig. 5 f = 1.0  MHz		-	560	-	рF		
Reverse Transfer Capacitance	C <sub>rss</sub>			-	120	-			
Drain to Sink Capacitance	С			-	12	-			
Total Gate Charge	Qg				-	-	72		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	l <sub>D</sub> = 17 /	A, V <sub>DS</sub> = 80 V, g. 6 and 13 <sup>b</sup>	-	-	11	nC	
Gate-Drain Charge	Q <sub>gd</sub>		000 11	j. o unu ro	-	-	32		
Turn-On Delay Time	t <sub>d(on)</sub>				-	11	-		
Rise Time	t <sub>r</sub>			-	44	-	ns		
Turn-Off Delay Time	t <sub>d(off)</sub>			-	53	-			
Fall Time	t <sub>f</sub>				-	43	-		
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH		
Internal Source Inductance	L <sub>S</sub>			-	7.5	-			
Drain-Source Body Diode Characteristic	s								
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the		-	-	17	A		
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode			-	-		68	
Body Diode Voltage	$V_{SD}$	$T_J = 25 \ ^\circ C, \ I_S = 17 \ A, \ V_{GS} = 0 \ V^b$		-	-	2.5	V		
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \ ^{\circ}C, \ I_F = 17 \ A, \ dl/dt = 100 \ A/\mu s^b$		-	180	360	ns		
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	1.3	2.6	μC		
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tur	n-on time i	s negligible (turn	-on is dor	ninated by	L <sub>S</sub> and I	_D)	

### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.





## TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



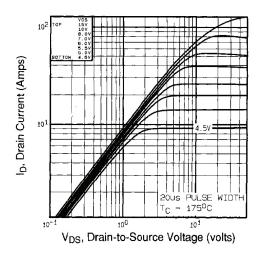


Fig. 2 - Typical Output Characteristics,  $T_C = 175$  °C

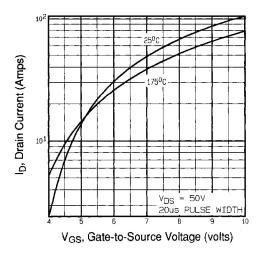


Fig. 3 - Typical Transfer Characteristics

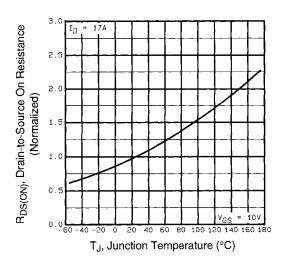


Fig. 4 - Normalized On-Resistance vs. Temperature

## PB210BTF



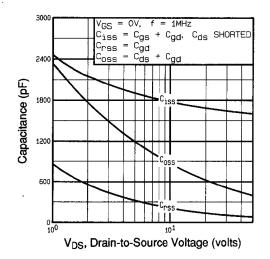


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

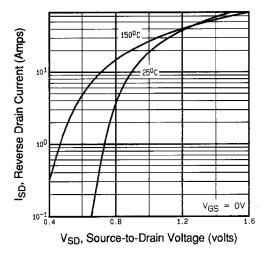


Fig. 7 - Typical Source-Drain Diode Forward Voltage

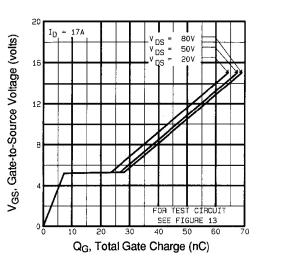


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

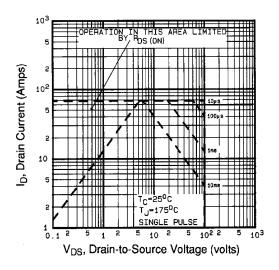


Fig. 8 - Maximum Safe Operating Area



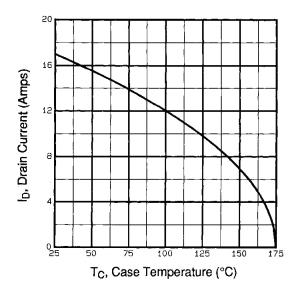


Fig. 9 - Maximum Drain Current vs. Case Temperature

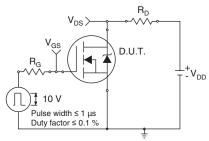


Fig. 10a - Switching Time Test Circuit

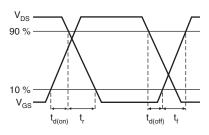


Fig. 10b - Switching Time Waveforms

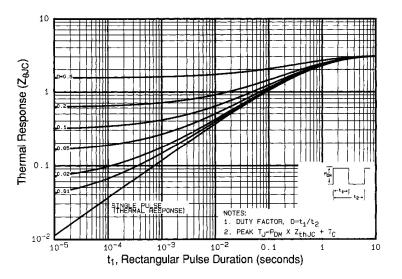


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

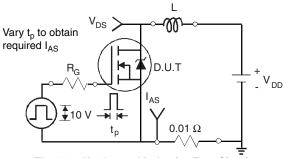


Fig. 12a - Unclamped Inductive Test Circuit

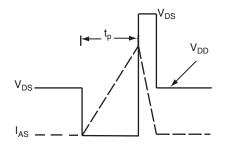


Fig. 12b - Unclamped Inductive Waveforms



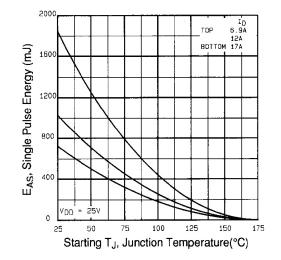


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

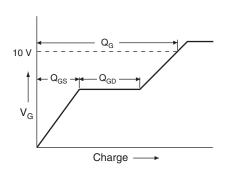
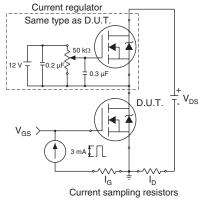
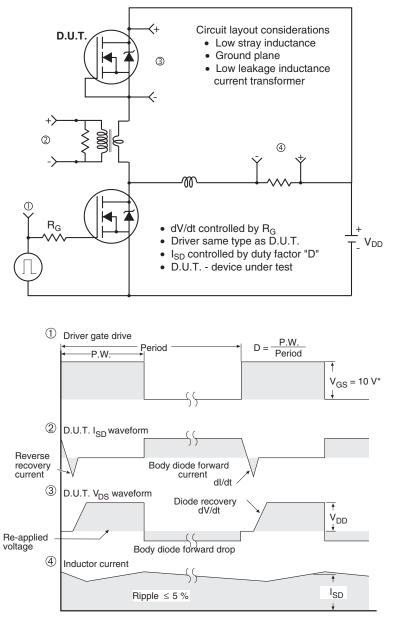


Fig. 13a - Basic Gate Charge Waveform









Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS}$  = 5 V for logic level devices

Fig.14 - For N-Channel



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